

April 1988 Revised June 2002

## 74F189

# 64-Bit Random Access Memory with 3-STATE Outputs

### **General Description**

The F189 is a high-speed 64-bit RAM organized as a 16-word by 4-bit array. Address inputs are buffered to minimize loading and are fully decoded on-chip. The outputs are 3-STATE and are in the high impedance state whenever the Chip Select  $\overline{(\text{CS})}$  input is HIGH. The outputs are active only in the Read mode and the output data is the complement of the stored data.

#### **Features**

- 3-STATE outputs for data bus applications
- Buffered inputs minimize loading
- Address decoding on-chip
- Diode clamped inputs minimize ringing

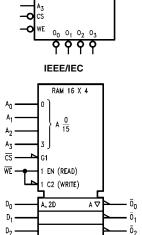
## **Ordering Code:**

Order Number	Package Number	Package Description
74F189SC	M16B	16-Lead Small Outline Intergrated Circuit (SOIC), JEDEC MS-013, 0.300" Wide
74F189SJ	M16D	16-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide
74F189PC (Note 1)	N16E	16-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300" Wide

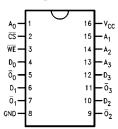
Devices also available in Tape and Reel. Specify by appending suffix "X" to the ordering code.

Note 1: This device not available in Tape and Reel.

## **Logic Symbols**



## **Connection Diagram**



# **Unit Loading/Fan Out**

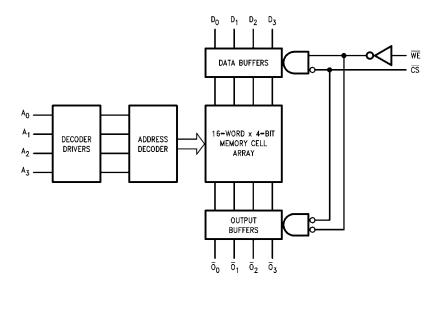
Din Names	Decembration	U.L.	Input I <sub>IH</sub> /I <sub>IL</sub>		
Pin Names	Description	HIGH/LOW	Output I <sub>OH</sub> /I <sub>OL</sub>		
A <sub>0</sub> -A <sub>3</sub>	Address Inputs	1.0/1.0	20 μA/–0.6 mA		
CS	Chip Select Input (Active LOW)	1.0/1.0	20 μA/–1.2 mA		
WE	Write Enable Input (Active LOW)	1.0/1.0	20 μA/–0.6 mA		
D <sub>0</sub> -D <sub>3</sub>	Data Inputs	1.0/1.0	20 μA/–0.6 mA		
$\overline{O}_0 - \overline{O}_3$	Inverted Data Outputs	150/40 (33.3)	-3.0 mA/24 mA (20 mA)		

## **Function Table**

Inputs		0	On distance Outputs			
cs	WE	Operation	Condition of Outputs			
L	L	Write	High Impedance			
L	Н	Read	Complement of Stored Data			
Н	X	Inhibit	High Impedance			

- H = HIGH Voltage Level L = LOW Voltage Level X = Immaterial

## **Block Diagram**



## Absolute Maximum Ratings(Note 2)

### **Recommended Operating Conditions**

-65°C to +150°C Storage Temperature Ambient Temperature under Bias

-55°C to +125°C

Free Air Ambient Temperature

0°C to +70°C

Junction Temperature under Bias

-55°C to +175°C

Supply Voltage

+4.5V to +5.5V

V<sub>CC</sub> Pin Potential to

Ground Pin -0.5V to +7.0VInput Voltage (Note 2) -0.5V to +7.0VInput Current (Note 2) -30 mA to +5.0 mA

Voltage Applied to Output

in HIGH State (with  $V_{CC} = 0V$ )

Standard Output

3-STATE Output

-0.5V to  $V_{CC}$  may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

 $-0.5V\ to\ +5.5V \\ \hline \textbf{Note 3: Either voltage limit or current limit is sufficient to protect inputs.}$ 

Note 2: Absolute maximum ratings are values beyond which the device

Current Applied to Output in LOW State (Max)

### **DC Electrical Characteristics**

Symbol	Parameter		Min	Тур	Max	Units	V <sub>CC</sub>	Conditions	
V <sub>IH</sub>	Input HIGH Voltage		2.0			٧		Recognized as a HIGH Signal	
V <sub>IL</sub>	Input LOW Voltage				0.8	V		Recognized as a LOW Signal	
V <sub>CD</sub>	Input Clamp Diode Voltage				-1.2	V	Min	I <sub>IN</sub> = -18 mA	
V <sub>OH</sub>	Output HIGH	10% V <sub>CC</sub>	2.5					I <sub>OH</sub> = -1 mA	
	Voltage	10% V <sub>CC</sub>	2.4			V		$I_{OH} = -3 \text{ mA}$	
		$5\% V_{CC}$	2.7			V	Min	$I_{OH} = -1 \text{ mA}$	
		$5\% V_{CC}$	2.7					$I_{OH} = -3 \text{ mA}$	
V <sub>OL</sub>	Output LOW Voltage	10% V <sub>CC</sub>			0.5	٧	Min	I <sub>OL</sub> = 24 mA	
I <sub>IH</sub>	Input HIGH		5.		<b></b>	μΑ	Max	V <sub>IN</sub> = 2.7V	
	Current				5.0				
I <sub>BVI</sub>	Input HIGH Current				7.0	μА	Max	V <sub>IN</sub> = 7.0V	
	Breakdown Test				7.0				
I <sub>CEX</sub>	Output HIGH				50	μА	Max	W -W	
	Leakage Current				50			$V_{OUT} = V_{CC}$	
V <sub>ID</sub>	Input Leakage		4.75			V	0.0	$I_{ID} = 1.9 \mu A$	
	Test		4.75			V	0.0	All Other Pins Grounded	
I <sub>OD</sub>	Output Leakage				3.75	μА	0.0	V <sub>IOD</sub> = 150 mV	
	Circuit Current				3.73	μА		All Other Pins Grounded	
I <sub>IL</sub>	Input LOW Current				-0.6			V <sub>IN</sub> = 0.5V (except CS)	
					-1.2	mA	Max	$V_{IN} = 0.5V (\overline{CS})$	
I <sub>OZH</sub>	Output Leakage Current				50	μА	Max	V <sub>OUT</sub> = 2.7V	
I <sub>OZL</sub>	Output Leakage Current				-50	μΑ	Max	V <sub>OUT</sub> = 0.5V	
Ios	Output Short-Circuit Currer	ıt	-60		-150	mA	Max	V <sub>OUT</sub> = 0V	
I <sub>ZZ</sub>	Bus Drainage Test				500	μА	0.0V	V <sub>OUT</sub> = 5.25V	
I <sub>CCZ</sub>	Power Supply Current			37	55	mA	Max	$V_O = HIGH Z$	

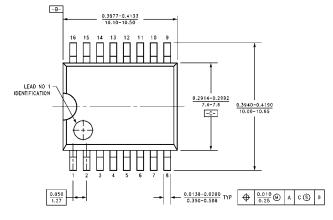
# **AC Electrical Characteristics**

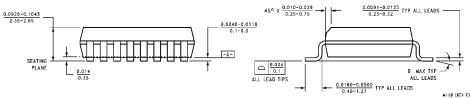
		$T_A = +25^{\circ}C$ $V_{CC} = +5.0V$			$T_A = -55^{\circ}C \text{ to } +125^{\circ}C$ $V_{CC} = +5.0V$		$T_A = 0$ °C to +70°C $V_{CC} = +5.0V$		Units	
Symbol	Parameter									
		C <sub>L</sub> = 50 pF			C <sub>L</sub> = 50 pF		$C_L = 50 \text{ pF}$			
		Min	Тур	Max	Min	Max	Min	Max		
t <sub>PLH</sub>	Access Time, HIGH or LOW	10.0	18.5	26.0	9.0	32.0	10.0	27.0	20	
t <sub>PHL</sub>	$A_n$ to $\overline{O}_n$	8.0	13.5	19.0	8.0	23.0	8.0	20.0	ns	
t <sub>PZH</sub>	Access Time, HIGH or LOW	3.5	6.0	8.5	3.5	10.5	3.5	9.5	ns	
t <sub>PZL</sub>	CS to O <sub>n</sub>	5.0	9.0	13.0	5.0	15.0	5.0	14.0		
t <sub>PHZ</sub>	Disable Time, HIGH or LOW	2.0	4.0	6.0	2.0	8.0	2.0	7.0		
t <sub>PLZ</sub>	CS to O <sub>n</sub>	3.0	5.5	8.0	2.5	10.0	3.0	9.0	ns	
t <sub>PZH</sub>	Write Recovery Time,	6.5	15.0	28.0	6.5	37.5	6.5	29.0		
t <sub>PZL</sub>	HIGH or LOW $\overline{\text{WE}}$ to $\overline{\text{O}}_{\text{n}}$	6.5	11.0	15.5	6.5	17.5	6.5	16.5	ns	
t <sub>PHZ</sub>	Disable Time, HIGH or LOW	4.0	7.0	10.0	3.5	12.0	4.0	11.0	20	
t <sub>PLZ</sub>	₩E to Ō <sub>n</sub>	5.0	9.0	13.0	5.0	15.0	5.0	14.0	ns	

# **AC Operating Requirements**

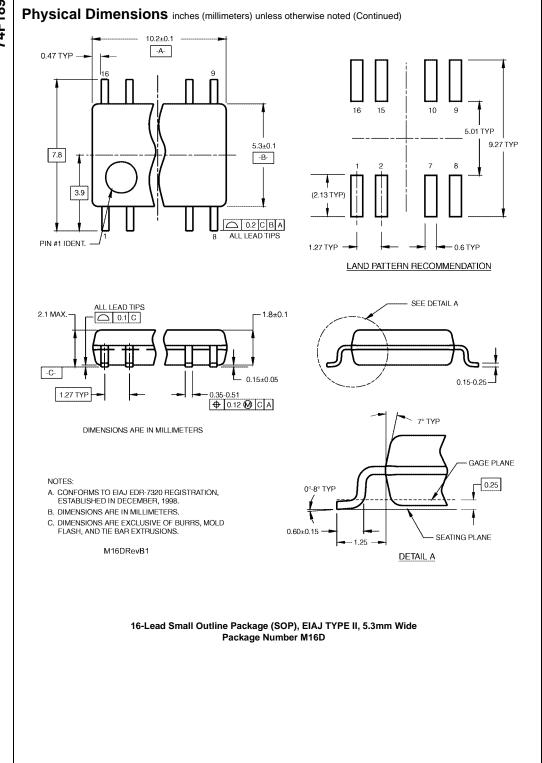
		$T_A = +25^{\circ}C$ $V_{CC} = +5.0V$		$T_A = -55^{\circ}C$	to +125°C	$T_A = 0^{\circ}C$ to $+70^{\circ}C$		
Symbol	Parameter			$V_{CC} = +5.0V$		$V_{CC} = +5.0V$		Units
		Min	Max	Min	Max	Min	Max	
t <sub>S</sub> (H)	Setup Time, HIGH or LOW	0		0		0		
$t_S(L)$	A <sub>n</sub> to WE	0		0		0		
t <sub>H</sub> (H)	Hold Time, HIGH or LOW	2.0		2.0		2.0		ns
$t_H(L)$	A <sub>n</sub> to WE	2.0		2.0		2.0		
t <sub>S</sub> (H)	Setup Time, HIGH or LOW	10.0		11.0		10.0		
$t_S(L)$	D <sub>n</sub> to WE	10.0		11.0		10.0		
t <sub>H</sub> (H)	Hold Time, HIGH or LOW	0		2.0		0		ns
$t_H(L)$	D <sub>n</sub> to WE	0		2.0		0		
t <sub>S</sub> (L)	Setup Time, LOW	0		0		0		
	CS to WE							
t <sub>H</sub> (L)	Hold Time, LOW	6.0		7.5		6.0		ns
	CS to WE							
t <sub>W</sub> (L)	WE Pulse Width, LOW	6.0		15.0		6.0		ns

# Physical Dimensions inches (millimeters) unless otherwise noted

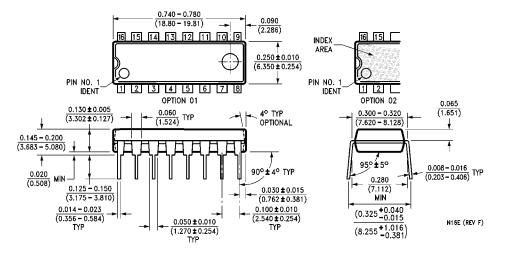




16-Lead Small Outline Intergrated Circuit (SOIC), JEDEC MS-013, 0.300" Wide Package Number M16B



### Physical Dimensions inches (millimeters) unless otherwise noted (Continued)



16-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300" Wide Package Number N16E

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